

IN THE SPECIFICATION

Please amend the Abstract by replacing as follows.

ABSTRACT

A semiconductor device test system capable of testing semiconductor devices having more pins than the test system. Adaptability and flexibility of the test system is enhanced when the number of its pins can be less than the number of pins of the semiconductor device to be tested. A pin electronics (PE) card includes a plurality of comparator and driver units. Each comparator and driver unit includes a driver for driving a predetermined input signal pattern to be applied to an input pin of the semiconductor device, and a comparator for comparing data from an output pin of the semiconductor device with a predetermined output signal pattern. The PE card also includes a plurality of control units for electrically connecting each of the comparator and driver units to a selected pin of the semiconductor device in response to a control signal. A pattern memory stores input and output signal patterns.